


<b>Search Notes</b>  	<b>Application/Control No.</b>  10530482	<b>Applicant(s)/Patent Under Reexamination</b>  MIYAJI ET AL.
	<b>Examiner</b>  Loewe, Sun Jae Y	<b>Art Unit</b>  1609

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
PALM inventor (all inventors)	7/2/07	sl
STN structure	7/2/07	sl
stn updated structure	11-26-2007	sl
STN: registry & caplus	6-12-2008	sl
PALM all inventors	6-12-2008	sl

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner